# Special Issue

# New Challenges on Cyber Threat Intelligence

### Message from the Guest Editors

This Special Issue aims to cover the latest techniques in all aspects and challenges, including the construction, operation, and sharing of cyber-threat intelligence systems. Theoretical and practical developments in the implementation and operation of cyber threat intelligence, the latest technical reviews, and surveys on CTI systems are welcomed. The topics of interest for this Special Issue include but are not limited to:

- Design and analysis of CTI system architecture;
- New operation strategy for CTI;
- Data representation model for CTI;
- Data sharing model for CTI;
- Data analysis methodology for CTI;
- Machine learning techniques and tools for CTI;
- Kill-chain model and application for CTI;
- Design and analysis of new evaluation method for CTI;
- Automated and smart tools for data collection, feature classification, and forensic analysis;
- Integration of incident response and digital forensic;
- Application of cyber security and intelligence;
- Reliability and risk analysis methodology for CTI;
- Cyberattack trend analysis model and system.

### **Guest Editors**

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### Deadline for manuscript submissions

closed (31 December 2021)



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## Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guestedited by leading experts in selected topics of interest.

### Editor-in-Chief

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